

Short Courses and Workshops

GEORGIA INSTITUTE OF TECHNOLOGY

Rietveld Method Short Course

The Rietveld method is widely recognized to be uniquely valuable for structural analysis of nearly all crystal-structure and related analyses of nearly all crystalline materials not available as single crystals. This 3-day intensive course will be conducted by Professors R. B. Von Dreele and R. A. Young, both well known in the field. The course will deal with the principles and techniques of Rietveld analysis and with avoiding or overcoming problems encountered in the use of it. The teaching system involves morning lectures, supervised individual hands-on experience running Rietveld refinements on PC-type computers in the afternoon, much student-teacher interaction and discussion, and availability of the computers at other times for further individual practice. The student will have a choice of using either of the two most widely used Rietveld programs, DBWS and GSAS. Both the well-grounded beginner and the moderately experienced user should find the course valuable.

Date: 5-7 May 1997
Location: Atlanta, GA
Conducted by: Georgia Tech Continuing Education
Program fee: \$899 (includes monograph and copies of computer programs & examples)
For more information: Department of Continuing Education
Georgia Institute of Technology
Atlanta, Georgia 30332-0385
Phone: 404/894-2547
E-mail: conted@gatech.edu

ICDD CLINIC ON X-RAY POWDER DIFFRACTION

Fundamentals of X-ray Powder Diffraction

2-6 June 1997

Advanced Methods in X-ray Powder Diffraction

9-13 June 1997

The ICDD XRD clinics will be held in two separate week-long sessions. The Fundamentals course will cover instrumentation, specimen preparation, data acquisition and

qualitative phase analysis. The Advanced Methods course will place emphasis on computer-based methods of data collection and interpretation, both for qualitative and quantitative phase analysis.

Sponsored by: International Centre for Diffraction Data (ICDD)
Location: ICDD Headquarters, Newtown Square, PA
Fee: \$1,150 per session
Contact: Theresa Maguire
International Centre for Diffraction Data
12 Campus Boulevard
Newtown Square, PA 19073-3273, USA.
Phone: (610) 325-9814; FAX: (610) 325-9823
E-mail: Clinics@ICDD.com

ICDD CLINIC ON X-RAY FLUORESCENCE SPECTROMETRY

Fundamentals of X-ray Fluorescence Spectrometry

16-20 June 1997

Advanced Methods in X-ray Fluorescence Spectrometry

23-27 June 1997

The ICDD XRD clinics will be held in two separate week-long sessions. The Fundamentals course will cover the basics of X-ray spectra, instrumentation design, methods of qualitative and quantitative analysis, specimen preparation and applications for both wavelength and energy dispersive spectrometry. The Advanced Methods course will place emphasis on quantitative methods, use of automated X-ray spectrometers, review of mathematical matrix correction procedures, and new developments in XRF.

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Commercial Announcement

X-RAY ANALYSIS RÖNTGENANALYTIK: SIEMENS REORGANISATION

The Siemens Automation Group (AUT) of Siemens Corporation has founded a limited company called AXS Analytical X-ray Systems GmbH (Systeme für die Röntgenanalytik). Located in Karlsruhe (Germany), the new company will take over all activities previously performed by AUT's X-ray business unit. On 1 October the Analytical Instrumentation business unit of the U.S. company Siemens Energy & Automation, Inc., a subsidiary of Siemens Corporation, will also be integrated.

This step was initiated in order to unify all business-relevant functions and operations under one single responsibility. This new structure will allow customers' requests to be satisfied quicker and more directly.

Both newly formed companies will maintain their individual centers of expertise built upon a 75-year heritage of technological innovation and excellence. With its broad spectrum in analytical X-ray systems, Siemens has gained a leading position in the world market.

Worldwide activities of AXS include the production, R&D, sales and services of X-ray analytical systems which are used in a broad range of industry, research and development for nondestructive multielement and structure analysis. Applications are in biotechnology, pharmaceutical and materials research, as well as in automated production and quality control. Three different methods are used in a wide range of applications, X-ray fluorescence (XRF) analysis, X-ray diffraction (XRD), and single-crystal diffraction (SCD).